

Application/Control No.	Applicant(s)/Patent under Reexamination
10/695,190	TSUKUDA ET AL.
Examiner	Art Unit
LaTanya Bibbins	2633

SEARCHED				
Class	Subclass	Date	Examiner	
369	44.37	7/13/2006	LB	
369	44.38	7/17/2006	LB	
250	559.38	7/18/2006	LB	
356	4.08	7/18/2006	LB	
356	624	7/18/2006	LB	
369	44.36	7/18/2006	LB	
369	53.19	7/18/2006	LB	
369	44.11	7/18/2006	LB	
356	615	7/24/2006	LB	
.356	622-624	7/24/2006	LB	
250	559.29	7/24/2006	LB	
250	559.31	7/24/2006	LB	

INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
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SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
Databases Searched: USPAT, PSPGPub, USOCR, EPO, JPO, DERWENT, IBM_TDB (see search history attached)	7/12/2006	LB
NPL searches including Google, IEEE Xplore, Inspec, and Optics Information Database (search terms are the same as EAST)	7/12/2006	LB
Inventor Name Search (PALM and EAST)	7/12/2006	LB
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